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| Notice of References Cited | | Application/Con. 09/615,564 | Applicant(s)/Patent Under Reexamination LEIFER ET AL. | |
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U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification | |
|---|---|--|-----------------|---------------|----------------|-----|
| | A | US-6260984 | 07-2001 | Naghi et al | 362 | 186 |
| | B | US-5165779 | 11-1992 | Tortola et al | 362 | 109 |
| | C | US-5325278 | 06-1994 | Tortola et al | 362 | 109 |
| | D | US- | | | | |
| | E | US- | | | | |
| | F | US- | | | | |
| | G | US- | | | | |
| | H | US- | | | | |
| | I | US- | | | | |
| | J | US- | | | | |
| | K | US- | | | | |
| | L | US- | | | | |
| | M | US- | | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
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NON-PATENT DOCUMENTS

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|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

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